

SEMI Standards Staff Report

April 23, 2018

SEMI Japan

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SEMI Global 2018 Calendar of Events

Event Name	Event Details
	<p>April 19 -20, 2018 Tokyo, Japan</p>
	<p>May 22 - 24, 2018 Kuala Lumpur, Malaysia</p>
	<p>July 10-12, 2018 San Francisco, California</p>
	<p>Sept 5-7, 2018 Taipei, Taiwan</p>
	<p>Nov 13-16, 2018 Munich, Germany</p>
	<p>Dec 12-14, 2018 Tokyo, Japan</p>

Schedule changed due to the country's election

SEMICON West Visitor Registration

- West '18 Visitor Registration is now open
- Free Expo Only Registration for STANDARDS
 - PROMO CODE : STAN2018

Register Today!

<http://www.semiconwest.org/>

Global Standards Meeting Schedule

<http://www.semi.org/en/standards-events>



- Apr 20, 2018
FPD Metrology Taiwan TC Chapter Meeting
Hsinchu, Taiwan
- Apr 20, 2018
Automation Technology Japan TC Chapter Meeting
Tokyo, Japan
- Apr 20, 2018
Silicon Wafer Japan TC Chapter Meeting
Tokyo, Japan
- Apr 23, 2018
Liquid Chemicals Japan TC Chapter Meeting
Tokyo, Japan
- Apr 24, 2018
EHS Japan TC Chapter Meeting
Tokyo, Japan
- Apr 24, 2018
Gases Japan TC Chapter and Facilities Japan TC Chapter Joint Meeting
Tokyo, Japan
- Apr 26, 2018
Physical Interfaces & Carriers Japan TC Chapter Meeting
Tokyo, Japan
- Apr 26, 2018
Information & Control Japan TC Chapter Meeting
Tokyo, Japan
- Apr 26, 2018
Automation Technology Taiwan TC Chapter Meeting
Taoyuan City, Taiwan
- May 10, 2018
3D Packaging and Integration Taiwan TC Chapter
Hsinchu, Taiwan
- May 11, 2018
FPD Materials & Components Japan TC Chapter
Tokyo, Japan
- May 16, 2018
PV Taiwan TC Chapter
ITRI Office (Meeting Room 534, Taipei Nangang Exhibition Center, Taipei City, Taiwan)
- May 18, 2018
Metrics Japan TC Chapter
Tokyo, Japan
- May 21, 2018
3D Packaging and Integration Japan TC Chapter
Tokyo, Japan
- May 26, 2018
PV&PV Materials China TC Chapters joint Meeting
Shanghai, China
- June 8, 2018
Information & Control Korea TC Chapter
SEMI Korea Office, Seoul, Korea
- July 10-12, 2018
SEMICON West 2018
San Francisco, California, USA
- November 5-8, 2018
NA Standards Fall 2018 Meetings
SEMI HQ in Milpitas, California, USA
- April 1-4, 2019 (tentative)
NA Standards Spring 2019 Meetings
SEMI HQ in Milpitas, California

As of April 17, 2018
Please make sure most updated
information in the above URL

2018 Critical Dates for SEMI Standards Ballots

Cycle	Ballot Submission Date	Voting Period Starts	Voting Period ends
Cycle 1	January 3	January 16	February 15
Cycle 2	February 7	February 21	March 23
Cycle 3	March 9	March 23	April 23
Cycle 4	April 20	April 30	May 30
Cycle 5	May 11	May 25	June 25
Cycle 6	July 20	August 1	August 31
Cycle 7	August 22	September 5	October 5
Cycle 8	October 12	October 26	November 26
Cycle 9	November 14	November 28	December 28

A&R Ballot Review (2018)

A&R Cycle	Result	Notes
January 2018	 ISCA&RSCJan2018WebVotingSummaryv	5880: failed. Reason: The TC Chapter review of the Letter Ballot took place and completed on a date other than the date described in the Background Statement of the Letter Ballot, which is violation of ¶ 9.5 of the Regulations.
March 2018	 ISCA&RSCMarch2018WebVotingSummaryv	All passed.

SEMI Standards Publications

Publication Cycle	New	Revised	Reapproved	Withdrawn
April 2017	0	5	1	0
May 2017	0	4	6	0
June 2017	2*	4	0	0
July 2017	0	1	1	0
August 2017	3	2	1	0
September 2017	0	1	3	0
October 2017	1	12	2	0
November 2017	0	4	0	0
December 2017	1	6	1	0
January 2018	0	6	4	0
February 2018	1	7	5	0
March 2018	5	10	22	0

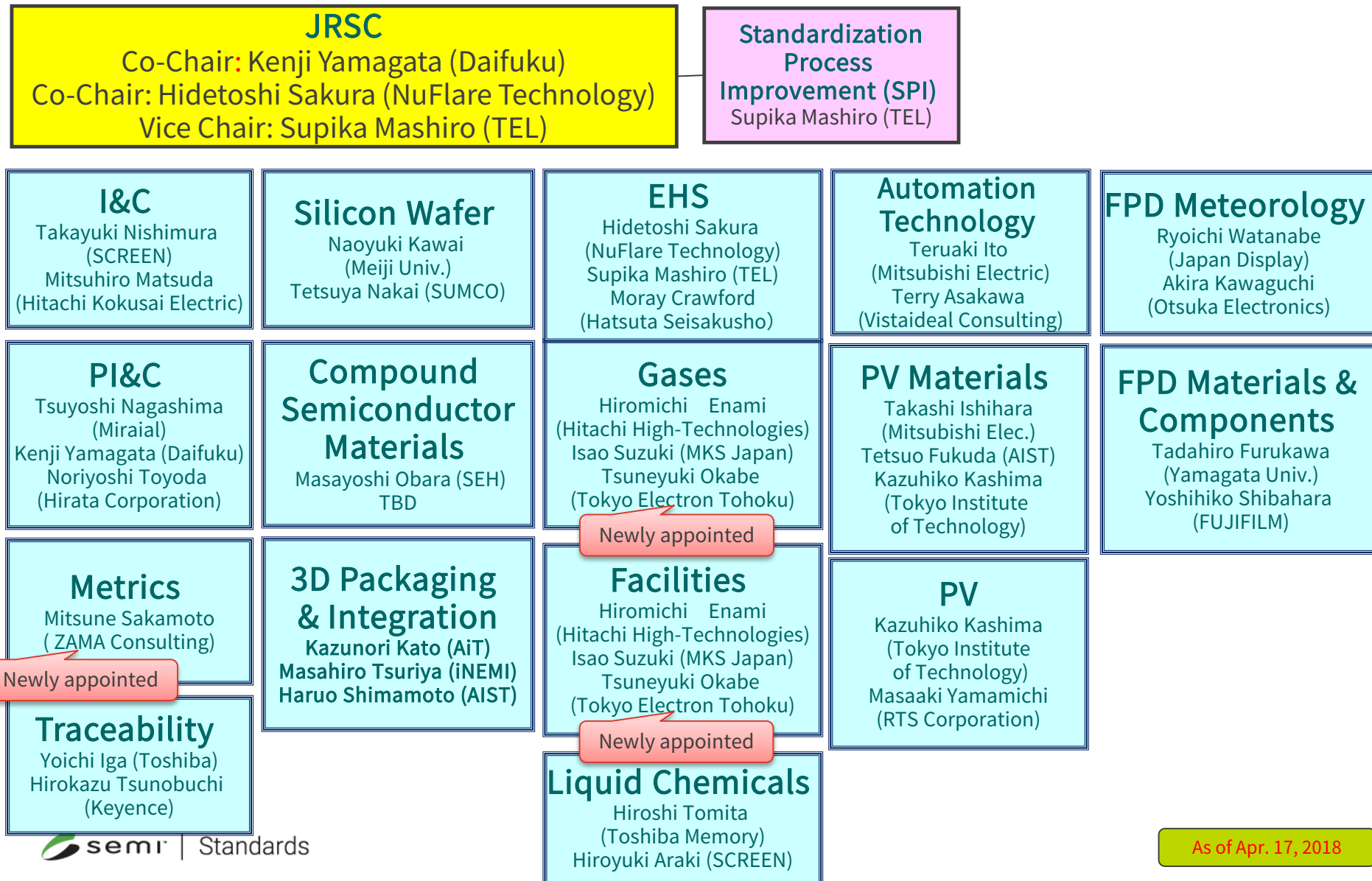
*Including New Auxiliary Document: 1

- Total SEMI Standards in portfolio: **985**
– Includes **225** Inactive Standards

New Standards published in April 2017 through March 2018

Doc #	Standards #	Title	GTC	Region
6088	SEMI A1-0617	Specification for Horizontal Communication (HC) Between Equipment for Factory Automation System	AT	Japan
5840	SEMI PV77-0817	Guide for Calibration of Photovoltaic (PV) Module UV Test Chambers	PV	China
5926	SEMI PV78-0817	Test Method for Bending Property of Flexible Thin Film Photovoltaic (PV) Modules	PV	China
6016	SEMI PV79-0817	Test Method for Exposure Durability of Photovoltaic (PV) Cells to Acetic Acid Vapor	PV	Japan
R5596A	SEMI E176-1017	Guide to Assess and Minimize Electromagnetic Interference (EMI) in a Semiconductor Manufacturing Environment	Metrics	North America
5822A	SEMI 3D17-1217	Specification for Reference Material for Bonded Wafer Stack Void Metrology	3D-IC	North America
R5634D	SEMI D75-0118	Test Method for Color Reproduction and Perceptual Contrast of Display	FPD - Metrology	Korea
5979	SEMI PV80-0218	Specification of Indoor Lighting Simulator Requirements for Emerging Photovoltaic	Photovoltaic	Taiwan
R5633F	SEMI D76-0318	Test Method for Viewing Angle Characteristic Using Reference Color on Visual Displays	FPD - Metrology	Korea
5925A	SEMI PV82-0318	Specification for Terrestrial Dual-Glass Module with Crystalline Silicon Solar Cell	Photovoltaic	China
5841A	SEMI PV81-0318	Guide for Specifying Low Pressure Horizontal Diffusion Furnace	Photovoltaic	China
5267A	SEMI MS11-0318	Specification for Microfluidic Port and Pitch Dimensions	MEMS	North America
5968A	SEMI PV83-0318	Guide for Sample Preparation Method for Photovoltaic Backsheet Performance Tests	Photovoltaic	China

JRSC Organization Chart



SEMI通信（2018年） SEMI Japan Newsletter (Monthly)

Articles are welcome!

- 2018_01_2017年度SEMIジャパン・スタンダード賞はSCREENセミコンダクターソリューションズの西村剛幸氏が受賞
- 2018_02_3D Packaging & Integrationグローバル技術委員会の始動とPLPパネルサイズ規格化の取り組み状況
- 2018_03_レガシィなパッケージ技術から三次元チップ実装技術、さらにFan-out Wafer LevelやPLP技術への標準化活動の遍歴について
- 2018_04_Fan-Out Wafer LevelやPLP技術への標準化活動の具体的な取り組み状況

Global Staff Assignment - North America

- Kevin Nguyen
 - Compound Semiconductor Materials
 - EHS
 - Microlithography
 - Photovoltaic
 - Photovoltaic Materials
 - Silicon Wafer
- Inna Skvortsova
 - Automated Test Equipment
 - Automation Technology
 - HB-LED
 - Information & Control
 - Liquid Chemicals
 - Metrics
 - Traceability
- Laura Nguyen
 - 3D Packaging & Integration
 - Facilities
 - Gases
 - MEMS / NEMS
 - Physical Interfaces & Carriers

Global Staff Assignment – Other regions

- China
 - Sophia Huang
 - HB-LED
 - PV
 - PV Materials
- EU
 - James Amano and Kevin Nguyen
 - Automation Technology
 - Compound Semiconductor Materials
 - Gases
 - Information & Control
 - Liquid Chemicals
 - Metrics
 - Physical Interfaces & Carriers
 - PV Materials
 - Silicon Wafer
- Korea
 - Natalie Shim
 - FPD Metrology
 - Facilities
 - HB-LED
 - Information & Control
- Taiwan
 - Dean Chang, Tiffany Huang
 - 3D Packaging & Integration
 - Automation Technology
 - EHS
 - FPD Metrology
 - Information & Control
 - PV

Staff Contact –Japan, After May 1, 2017

Committee	Staff
PV, PV Materials, Gases, Facilities, Liquid Chemical, I&C, Automation Technology	<i>Mizue Iwamura,</i> <i>Coordinator, Standards & EHS</i> <u>miwamura@semi.org</u>
FPD M&C, FPD Meteorology, PI&C, Metrics, Traceability, EHS, 3D Packaging & Integration	<i>Chie Yanagisawa</i> <i>Manager, Standards & EHS</i> <u>cyanagisawa@semi.org</u>
JRSC (including SPI TF), Compound, Silicon Wafer	<i>Junko Collins</i> <i>Director, Standards & EHS</i> <u>jcollins@semi.org</u>
Others	Staff
Standards Membership	<i>Mizue Iwamura</i>
Standards Products General Information, SEMIViews	<i>Chie Yanagisawa</i>
Other Standards Operation	<i>Junko Collins</i>

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Thank you